3MG2-P smart.md 6/27/2022

3MG2-P

SMART Definitions

Read Error Rate: 讀取錯誤率.

Reallocated Sectors Count: 當前備用磁區的總數,會隨着壞磁區的替換逐漸減少.

Power On Hours: 上電時間(小時), 一般為 30000 小時.

Power Cycle Count: 上電次數.

Uncorrectable Sector Count On Line: 在讀取/寫入下,無法校正磁區數.

Number of Pure Spare: 有效備用區塊數.

Number of Initial Block: 初始化無效區塊數.

Total Erase Count: 總共抹除數.
Max Erase Count: 最大抹除數.
Min Erase Count: 最小抹除數.
Average Erase Count: 平均抹除數.

Max Erase Count in Spec: 最大抹除數規格.

Remain Life Percentage: 剩餘壽命百分比((P/E Cycle - Average Erase Count) / P/E Cycle).

Worst Die Program Fail Count: 最差晶片中,程序失敗次數. Worst Die Erase Fail Count: 最差晶片中,抹除失敗次數.

WearLeveling Count: 快閃記憶體抹寫次數.
Used Reserved Block Count: 使用保留區塊數.

Program Fail Count:程序失敗次數. Erase Fail Count:抹除失敗次數.

Uncorrectable Error Count: 無法透過 ECC 修正的錯誤數量.

Power off Retract Count: 意外斷電次數.

Temperature: 設備溫度(-40~85).

Hardware ECC recovered: 每個磁區只要有 ECC, 次數會+1.

Reallocation Event Count:無法校正錯誤次數. Current pending sector count:等待移動磁區數.

Uncorrectable Sector Count OffLine: 離線時,無法校正總數.

UDMA CRC Error: **Device** 與 **Host** 之連接異常次數. Available Reserved Space: 可用的留存空間.

Write Sector Count: 寫入磁區次數. Read Sector Count: 讀取磁區次數.

Flash Write Count: 快閃記憶體寫入次數.